

Abstract

**SOCKET OR ADAPTER DEVICE FOR SEMICONDUCTOR DEVICES,
METHOD FOR TESTING SEMICONDUCTOR DEVICES, AND SYSTEM COM-
5 PRISING AT LEAST ONE SOCKET OR ADAPTER DEVICE**

The invention relates to a method for testing semiconductor devices, to a system including at least one socket or adapter device, and to a socket or adapter device, in particular for semiconductor devices, having at least one connection pin which is designed such that it is adapted to be introduced into a corresponding contact device of a device to which the socket or adapter device is to be connected, wherein the connection pin is designed such that a clamping connection is provided between the contact device and the connection pin when the connection pin is introduced into the contact device.

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- Figure 4 -

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